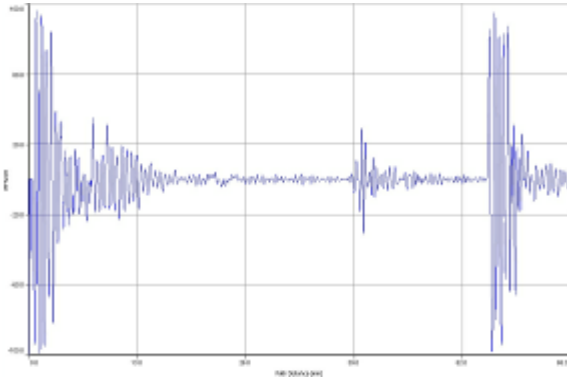


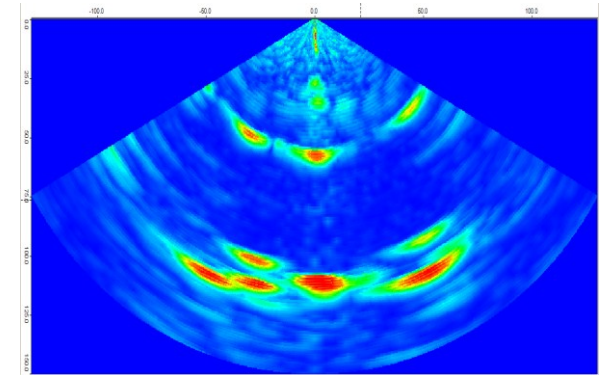
UT, μ -NDT, NDT Systems

Michael Kröning

RF A-SCAN



PA SECTOR-SCAN

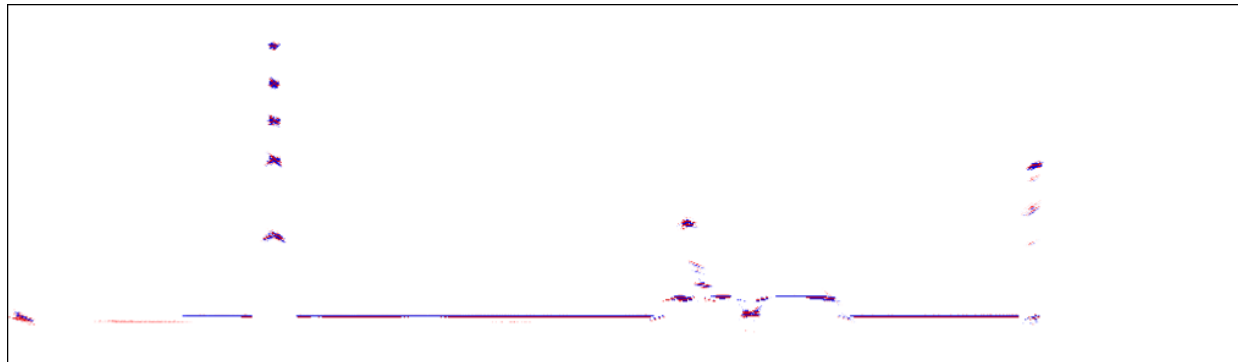


DEFINITIONS

APPLICATIONS

BASICS

CASE STUDIES



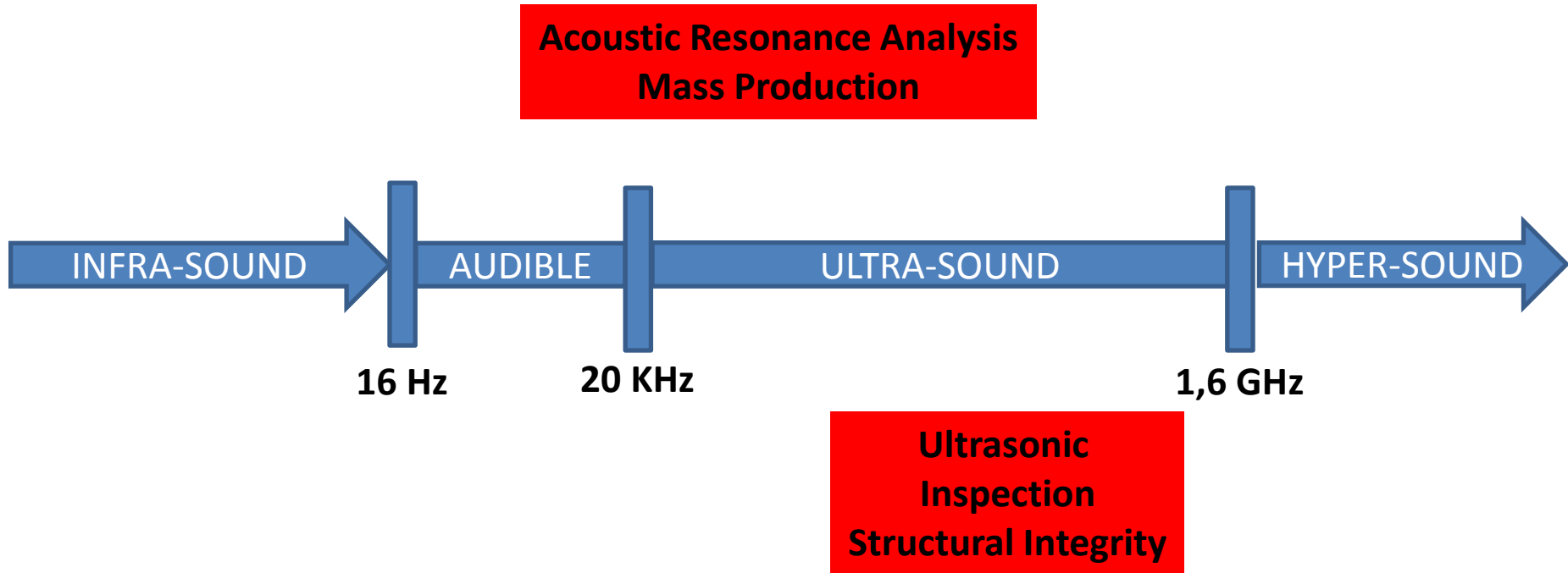
ADVANCED REAL-TIME IMAGING

UT, μ -NDT, NDT Systems

Method	Main Application	Relevance	Remarks
Pulse-Echo	Flaw Detection Geometry Measurement	★★★★★	Standard
Guided Waves	Long Range Inspection	★★	Pipe Systems
Continuous Waves	Elastic Properties; Distance Measurement	★ (Research)	Specific Use (Time Reversal)
Velocity	Stress State Material Characterization	★ (Research)	Specific Use
Frequency Response	Adhesive Strength Material Degradation	★ (Research)	Specific Use (Aerospace Materials)
Ultrasonic Microscopy	Microscopy; SAW Micro Structure Characterization	★ (Laboratory)	Specific Use (Electronic Structures)

ULTRASONIC TESTING

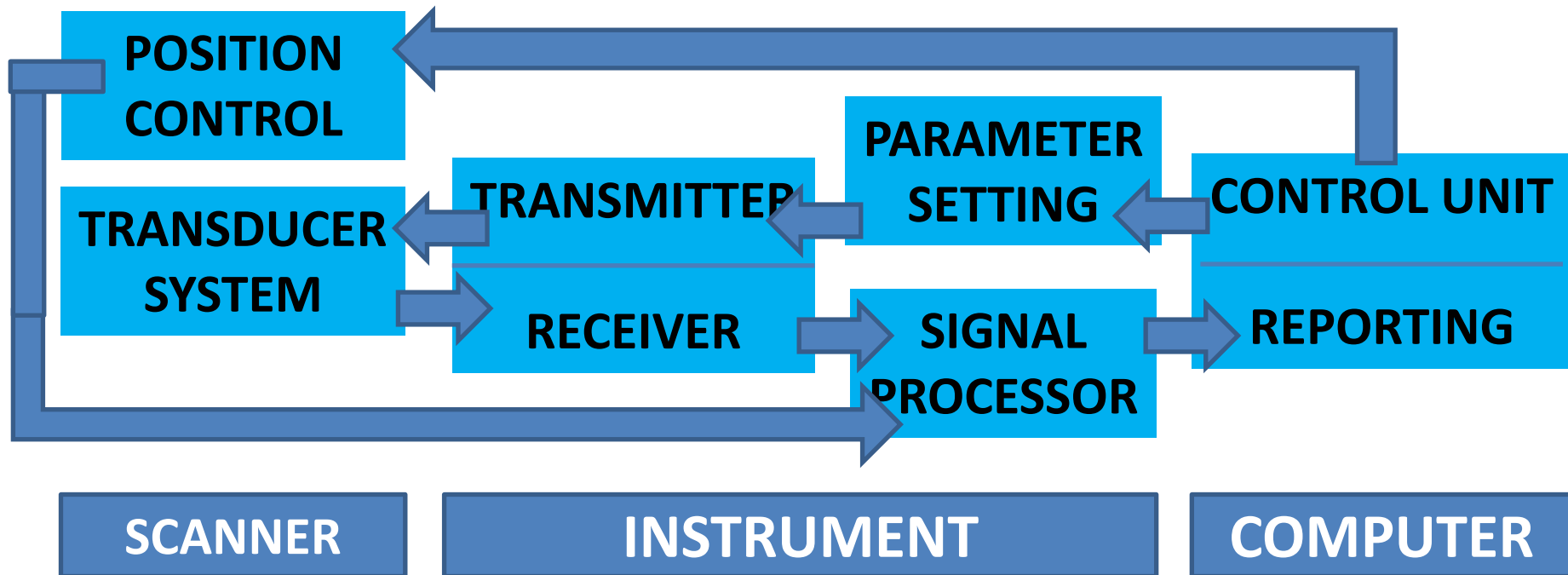
UT, μ -NDT, NDT Systems



FOCUS ON ULTRASONIC INSPECTION UT

BASICS of UT

FOREIGN CODES: ASME Section 5, EN 583 and others



STRUCTURE OF ULTRASONIC SYSTEMS

UT, μ -NDT, NDT Systems

BASICS of UT**SYSTEM ENGINEERING**

with

Advanced Modular Architecture

- **INSPECTION PROBLEM**
(Specification, Procedures, Constraints)
- **MEASUREMENT PHYSICS**
(Nondestructive Methods, Sensor Physics)
- **ELECTRONICS**
(Instruments, Computer Hardware)
- **INFORMATION TECHNOLOGIES**
(System Programming, Signal Processing, System Control & Reporting, Asset Management)
- **HANDLING TECHNOLOGIES**
(Robots, Automation Technologies)

BASICS of UT

TRANSDUCER TECHNOLOGIES

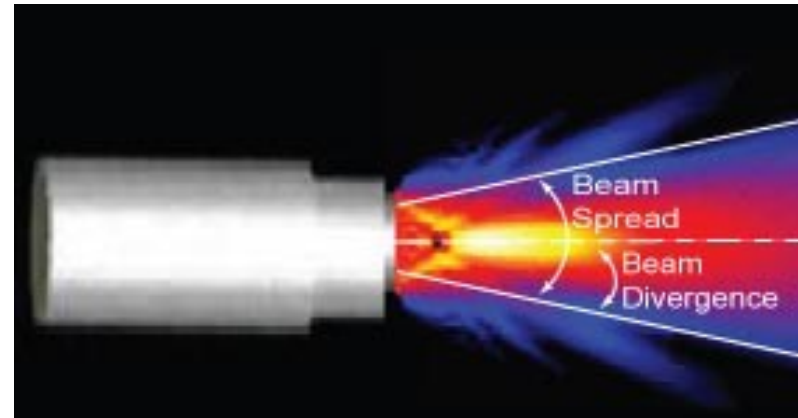
MECHANICAL
IMPACT

PIEZO
EFFECT

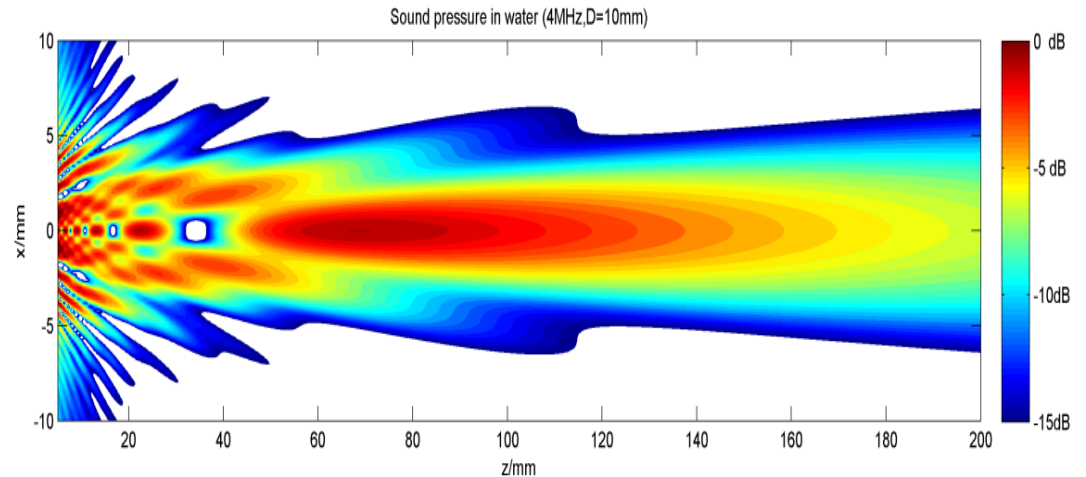
ELECTRO
MAGNETIC

LASER
IMPACT

EMAT



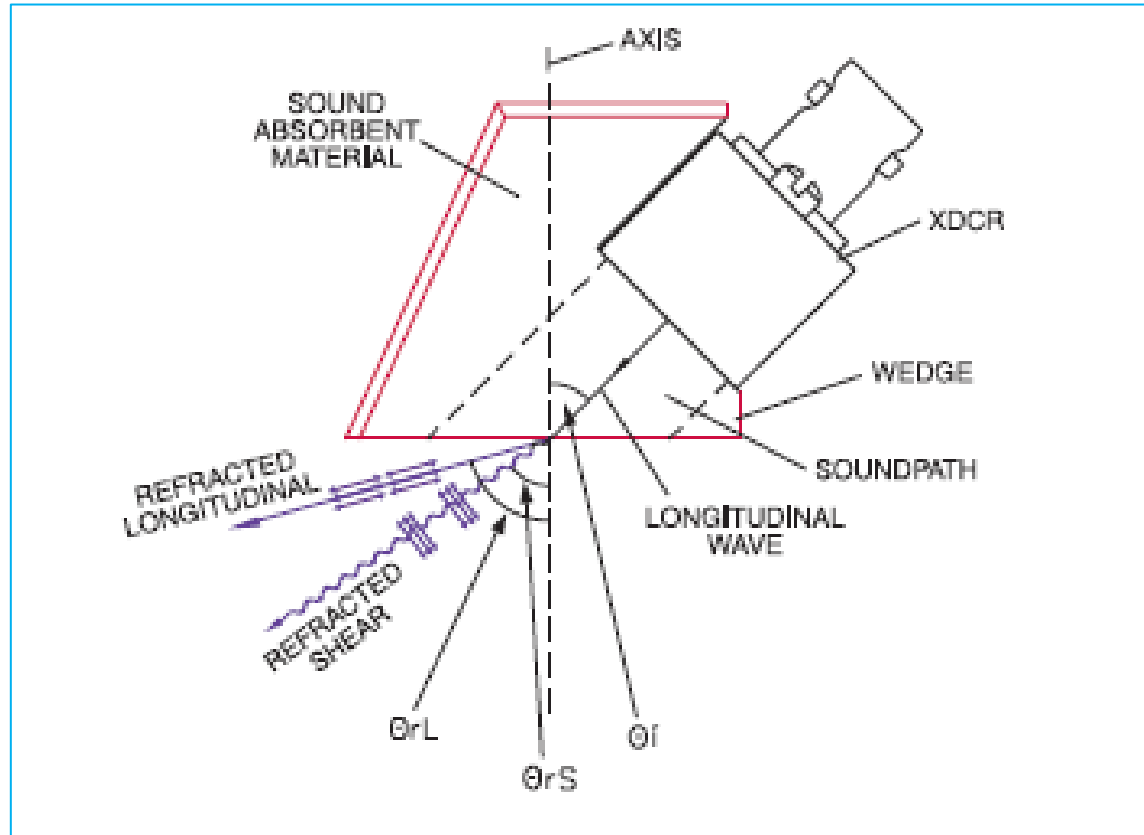
Typical Ultrasonic Sound Field (Larson, 2011)



Harmonic Sound Field with Near-field, Natural Focus, and Far-field

UT, μ -NDT, NDT Systems

BASICS of UT

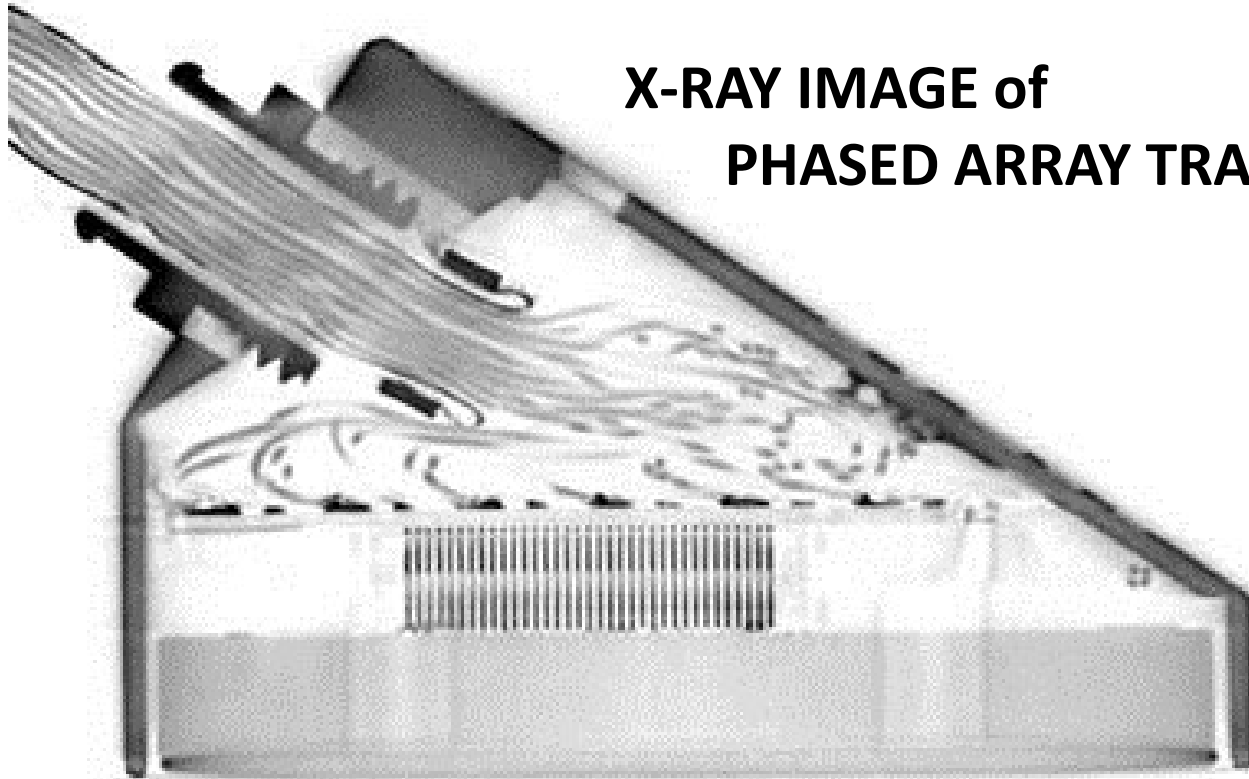


Typical Design of an Angular Beam Transducer (Olympus, 2011)

PIEZO TRANSDUCER

UT, μ -NDT, NDT Systems

BASICS of UT



**X-RAY IMAGE of
PHASED ARRAY TRANSDUCER**

BASICS of UT

Near field distance: $N = (A^2 - \lambda^2) / 4\lambda$

Transducer aperture: A

Wave length: λ

Focus diameter : $\vartheta \sim .26 A$

Focal length: Λ

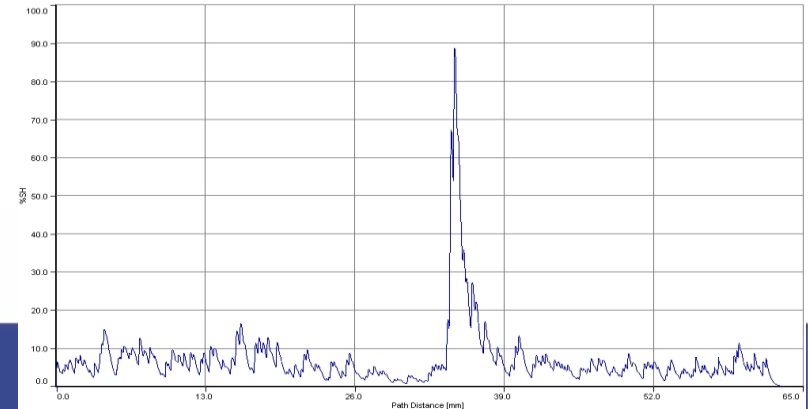
TECHNICAL ESTIMATES of TRANSDUCER PARAMETERS**PIEZO TRANSDUCER**

UT, μ -NDT, NDT Systems

BASICS of UT

Impulse – Echo Technique

SIMULATION



PIEZO TRANSDUCER

UT, μ -NDT, NDT Systems

Case Studies: Surfaces

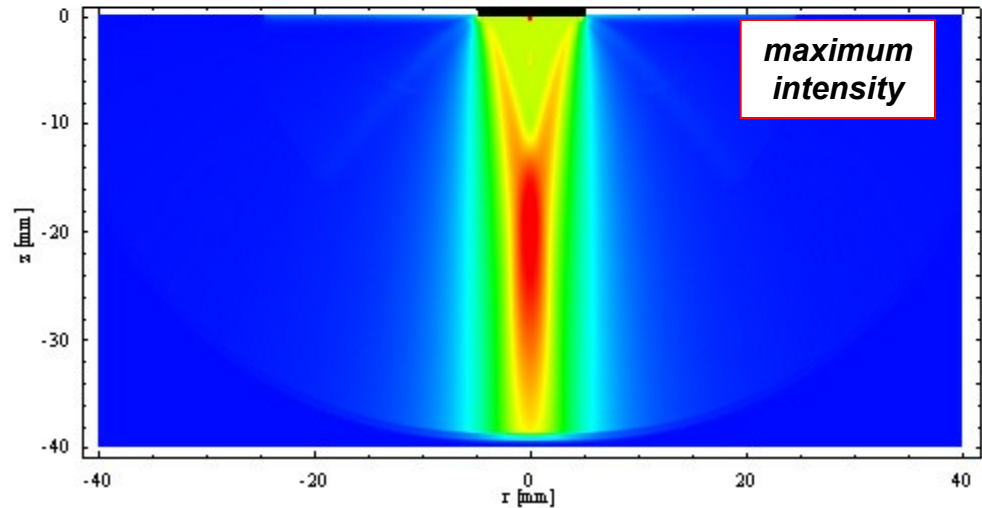
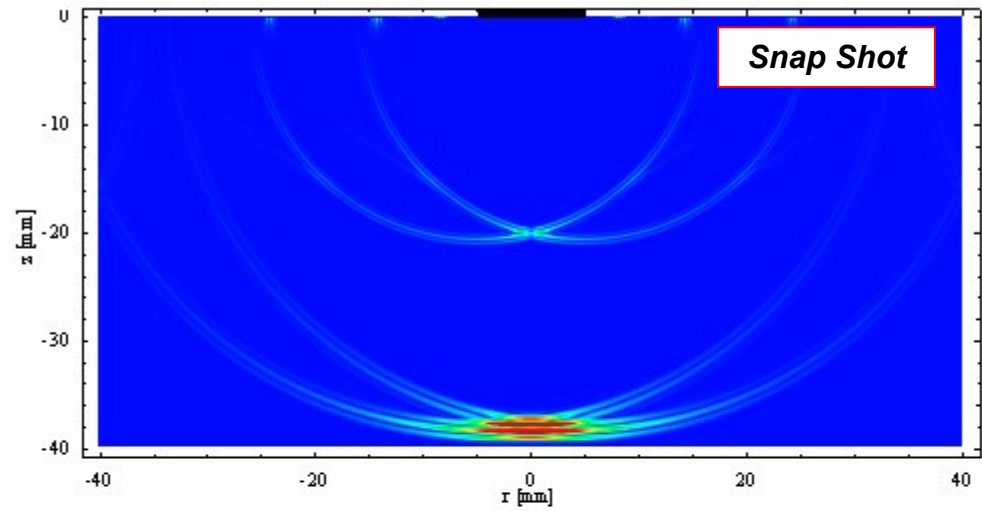
Simulation by Dr. Schubert

Fraunhofer IZFP-D

Transducer: normal probe
 $f = 4 \text{ MHz}$

Aperture: $A = 10 \text{ mm}$

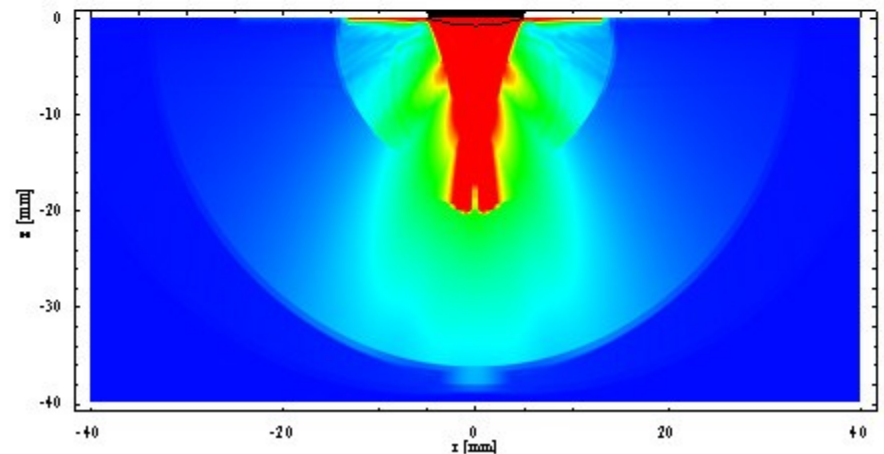
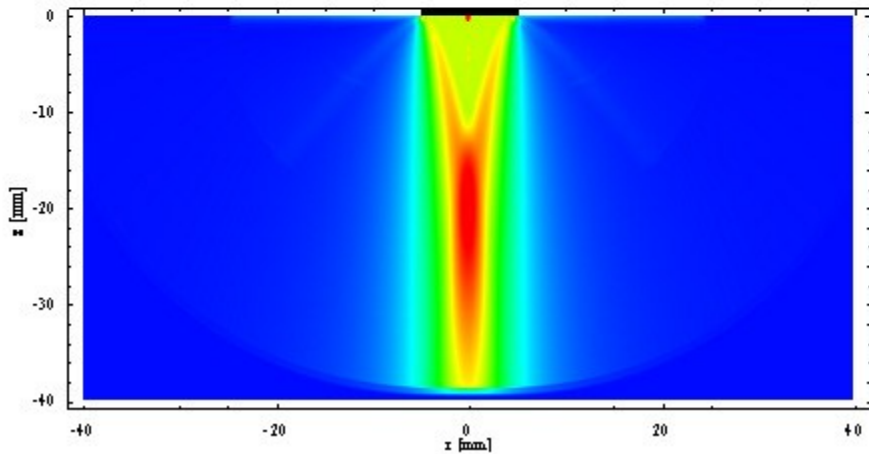
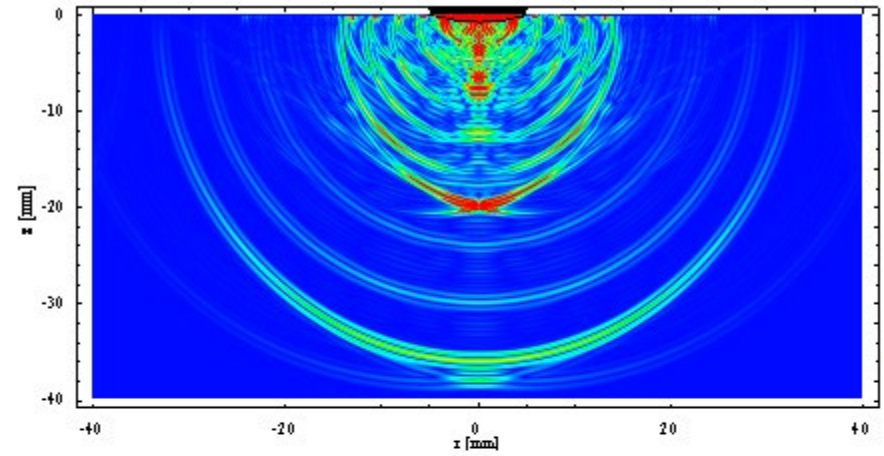
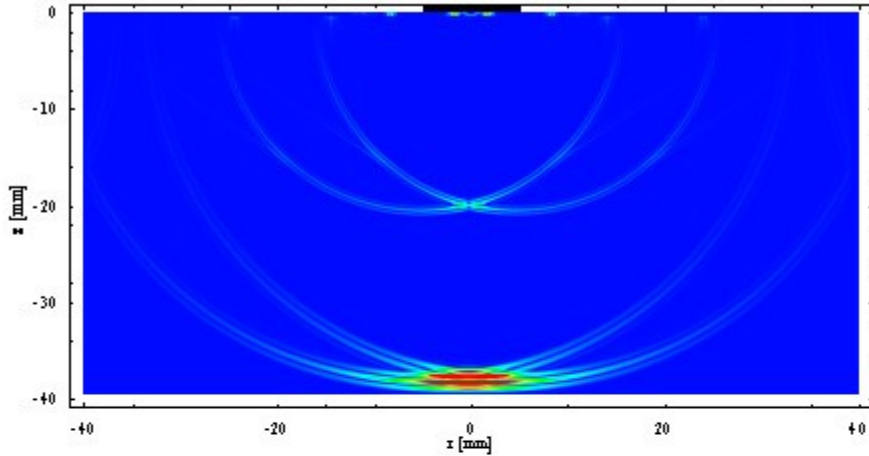
Surface: flat



COUPLING

UT, μ -NDT, NDT Systems

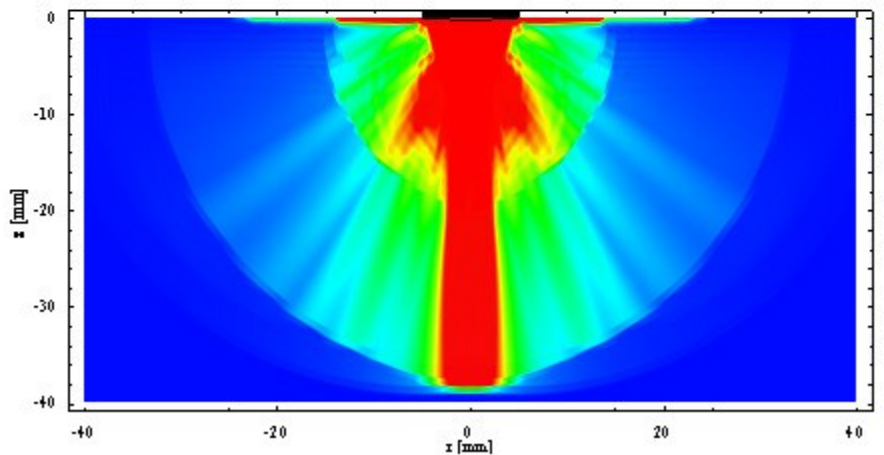
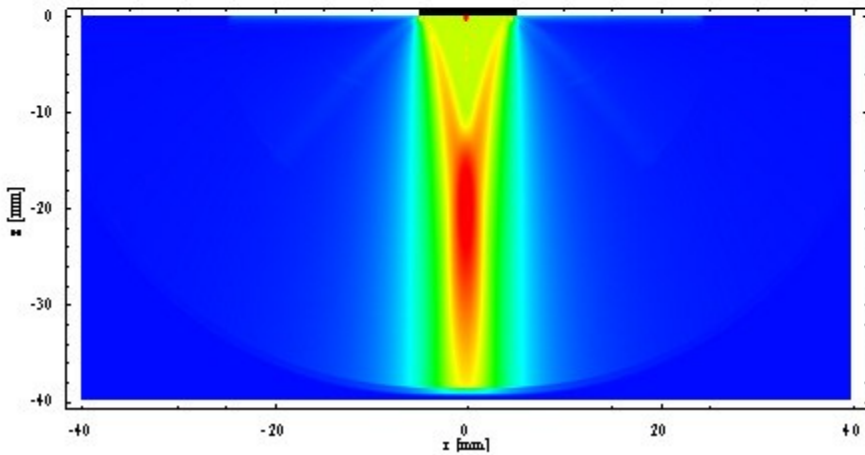
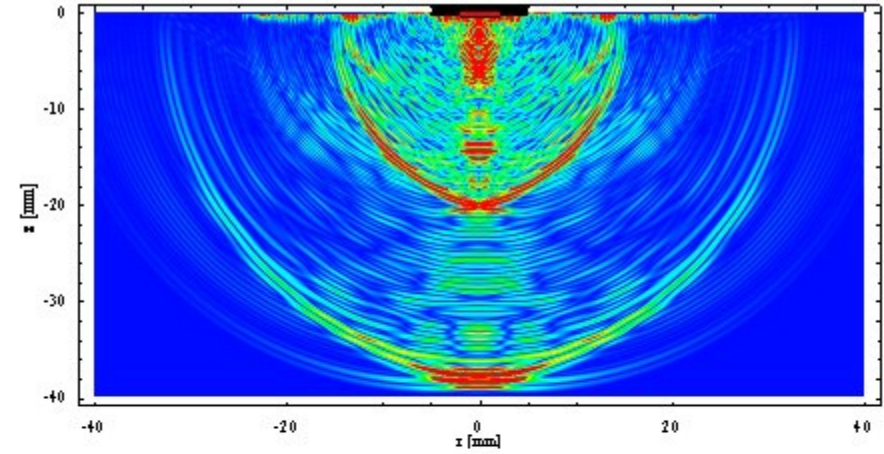
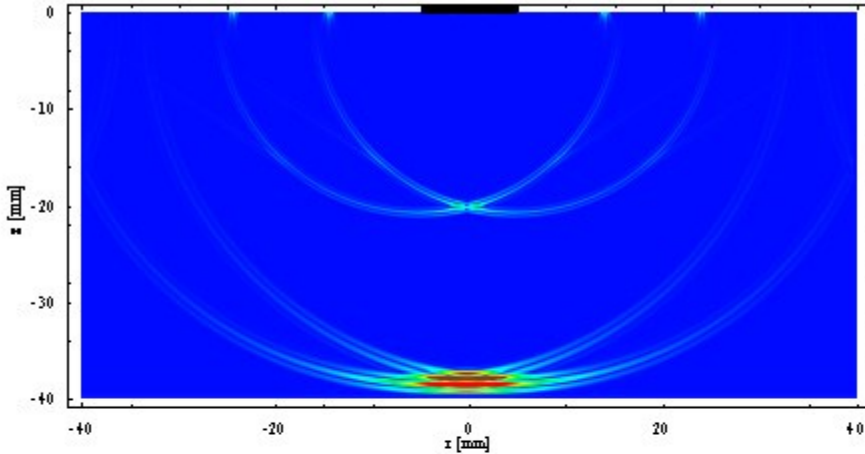
Water gap depth (lense shaped): 0.74 mm ($\lambda/2$ in steel, 2λ in water)



COUPLING

UT, μ -NDT, NDT Systems

Water gap depth (lense shaped): 0.18 mm ($\lambda/8$ in steel, $\lambda/2$ in water)



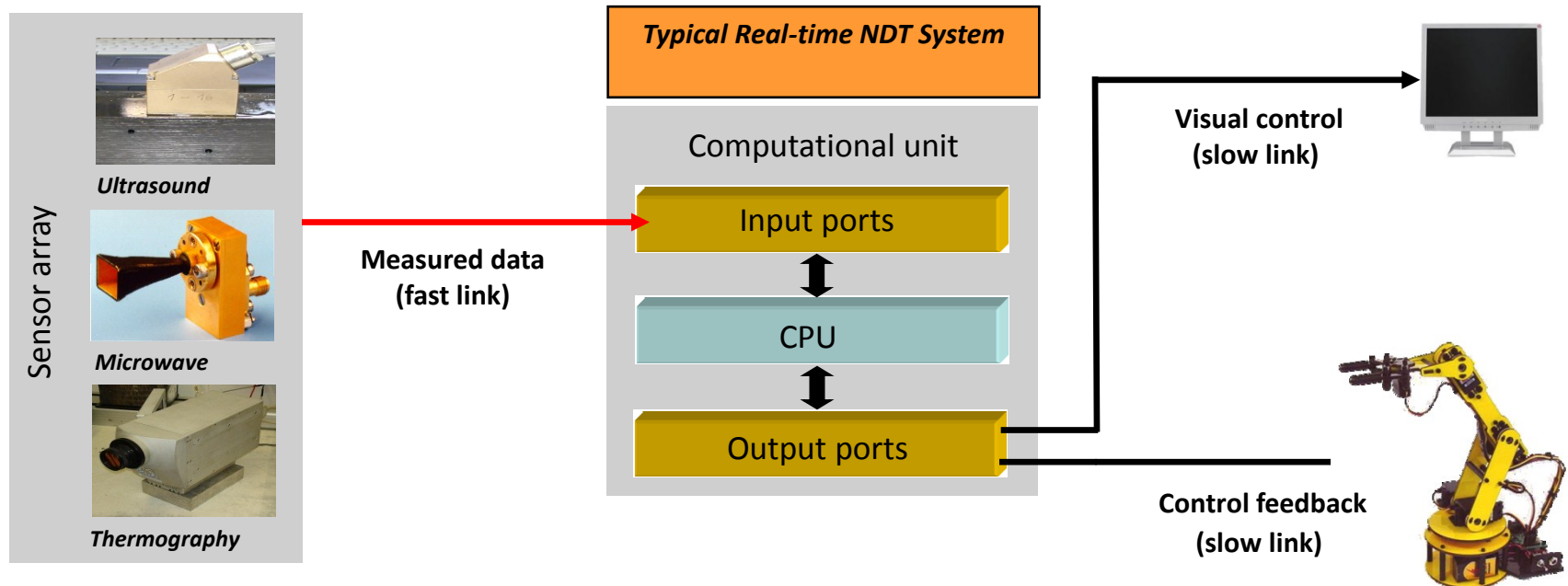
COUPLING

UT, μ -NDT, NDT Systems

Information Flow in NDT Systems

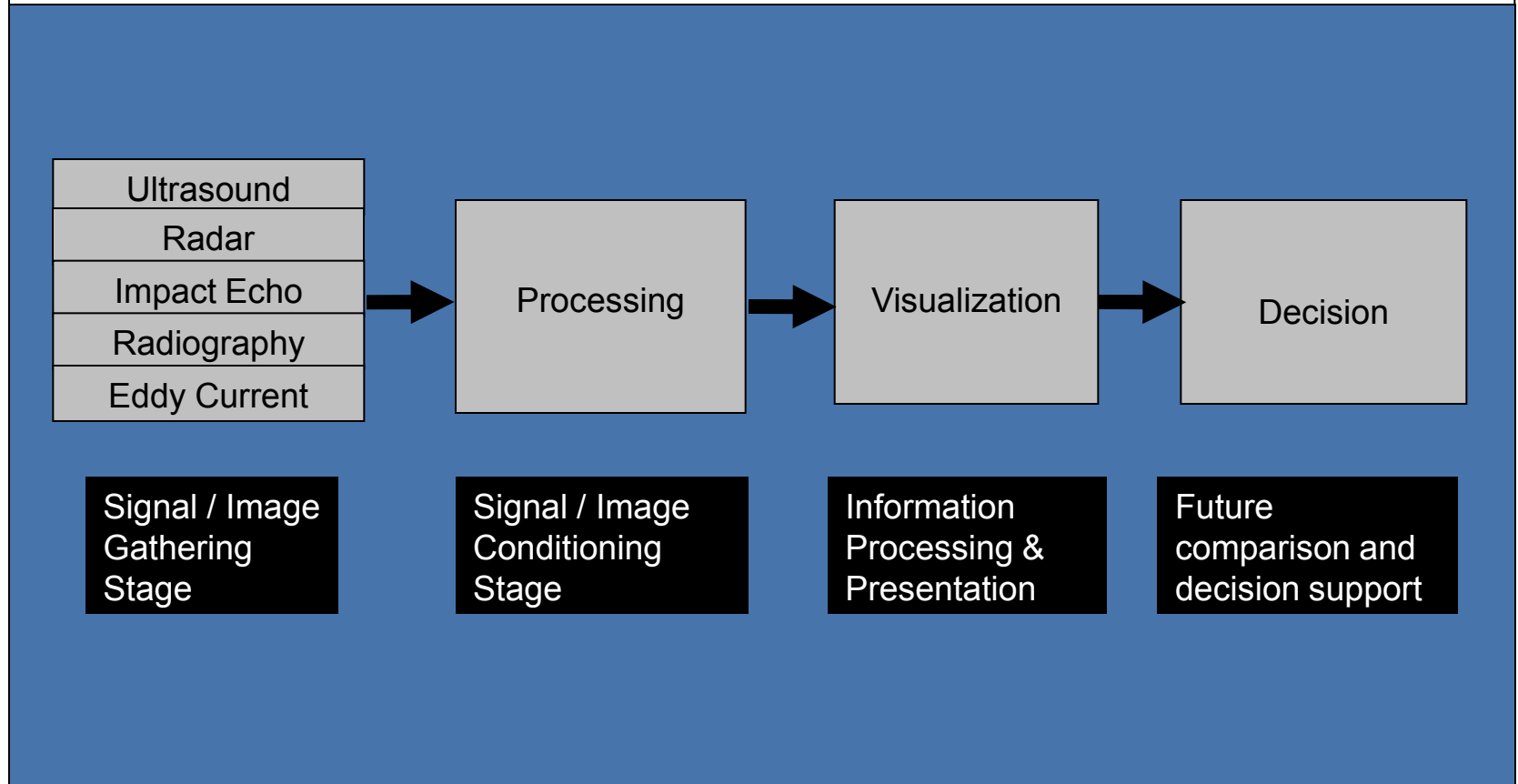
The complexity of data processing in modern NDT requires...

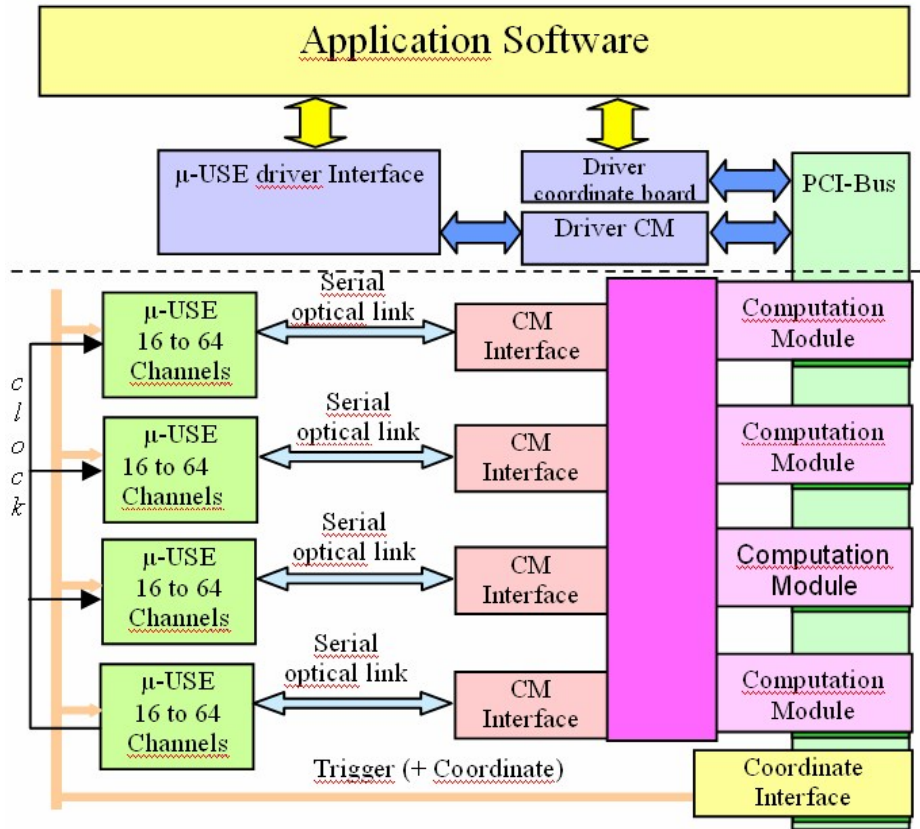
- Fast data links of several Gbit / sec (data transfer towards computational unit)
- Computational unit performance of hundreds of GFlop / sec (reconstruction process)



UT, μ -NDT, NDT Systems

Paradigm Shift – Data Centric

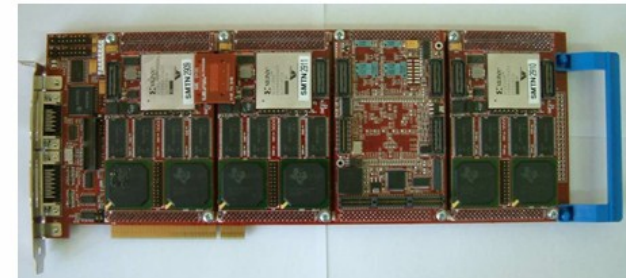




16-Channel μ -USE UT Front End



Multi-DSP Computation Module



Parallel architecture of A-scan recording and processing

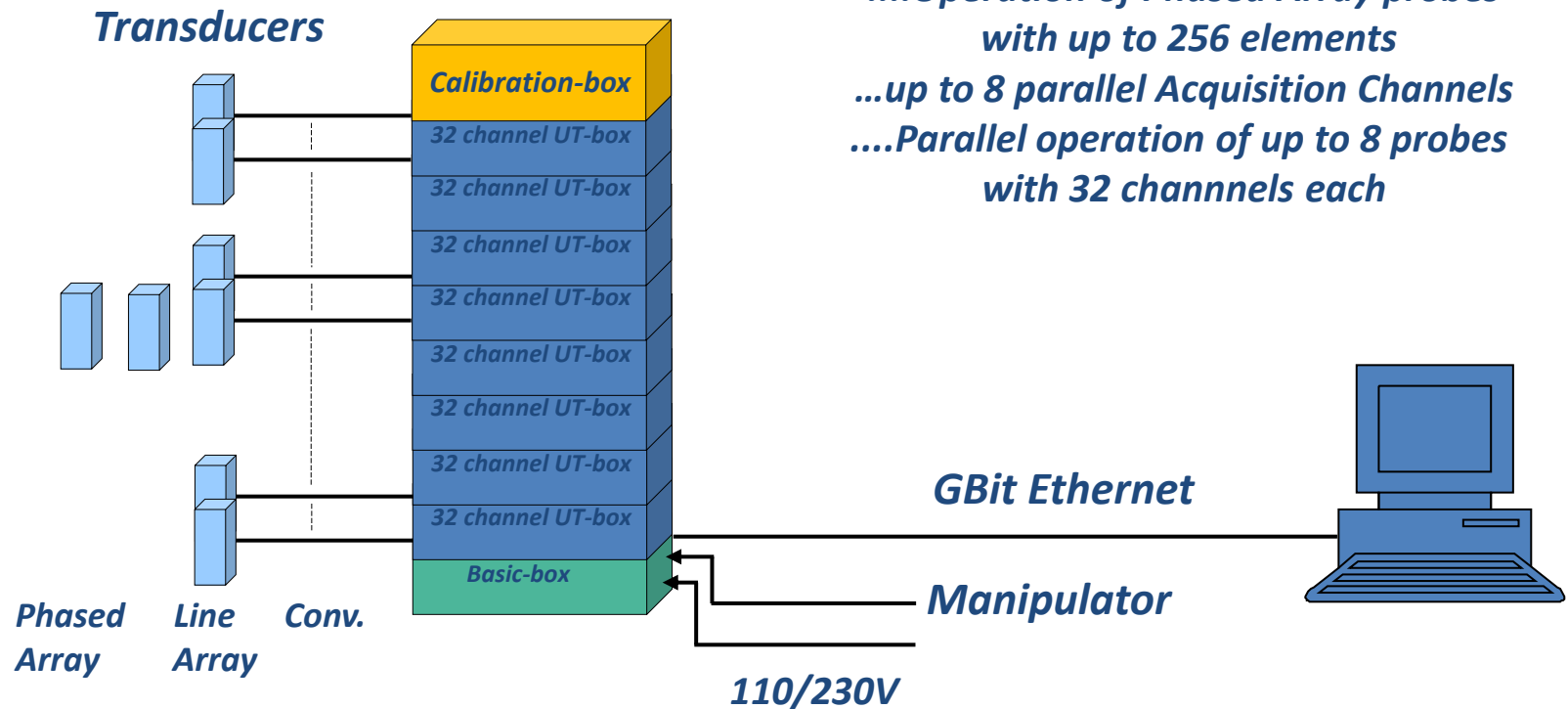
UT, μ -NDT, NDT Systems

SAPHIR^{quantum}

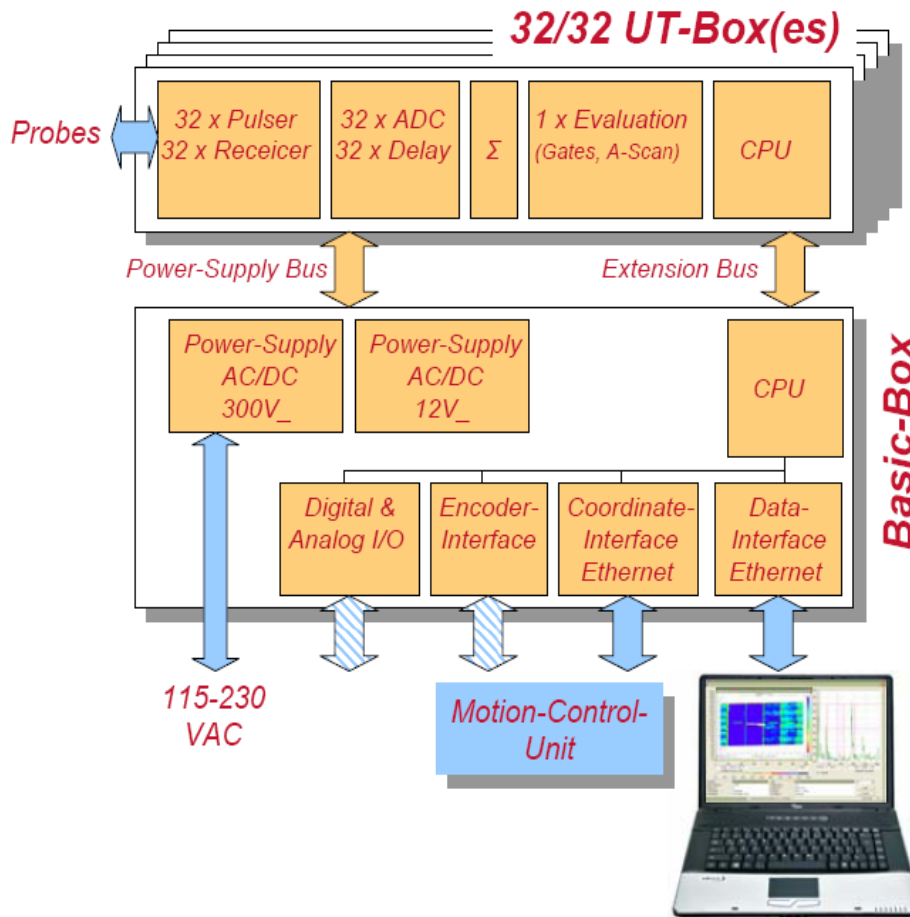
Multiple Boxes Configuration

Multiple Box Cascaded Version

- ...up to 256 UT-Channels simultaneously*
-Operation of Phased Array probes with up to 256 elements*
- ...up to 8 parallel Acquisition Channels*
-Parallel operation of up to 8 probes with 32 channels each*



SAPHIR^{quantum} System-Architecture



- **Flexible architecture**...starting from a portable equipment with 32 channels up to a complex configuration with 256 channels (1..8 UT-Boxes)
- **Parallel structure** with full 256/256 channels means no limits for the user...Phased-Array probes with up to 256 active elements, or a mix of a number of Phased-array and conventional probes
- High productivity by up to **8 parallel firing probes** in conjunction with the possibilities of the different on-board data-reduction methods & the GBit-Data-Interface

Calibration-Box

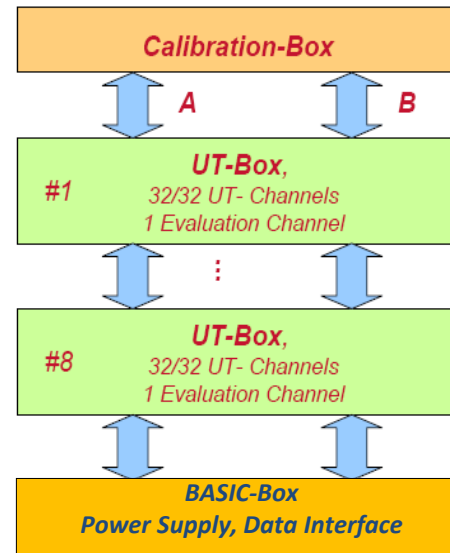
- Calibration for 32 Channels
- Cable-Channel-Check
- Extended Self-Check

32/32 UT-Box

- UT-Electronic with 32/32 channels
- Basic Self-check

Basic-Box

- Power-Supply for up to 8 Boxes
- Data- and Coordinate-Interfaces
- 110-230V Input



A = Extension Bus
B = Power-Supply Bus

Max. 8 UT-Boxes
→ 256/256 UT-Channels
→ 8 parallel Evaluation Channels

SAPHIR^{quantum} System-Architecture

UT, μ -NDT, NDT Systems

GRINM

General Research Institute for Nonferrous Metals

SEMINAR

R&D Laboratory on Industrial Demand



AUTOMATION FOR

REDUCTION OF HUMAN ERROR

ACCESS TO COMPONENT

SHORTER INSPECTION TIMES

LESS RADIATION EXPOSURE



UT, μ -NDT, NDT Systems

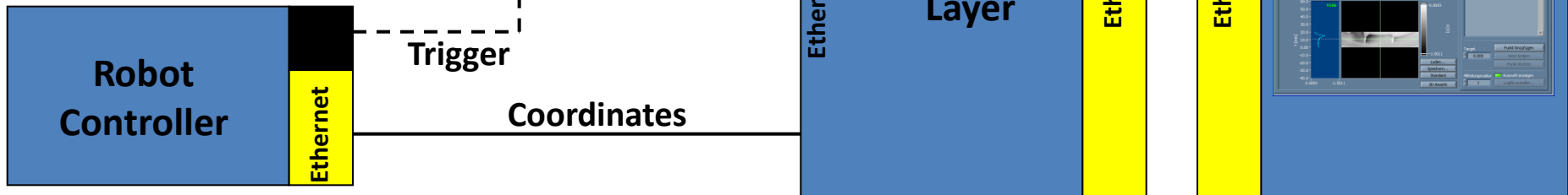
Robot



Measuring Device



PC



Architecture of Robotic NDT Systems

UT, μ -NDT, NDT Systems

GRINM

General Research Institute for Nonferrous Metals

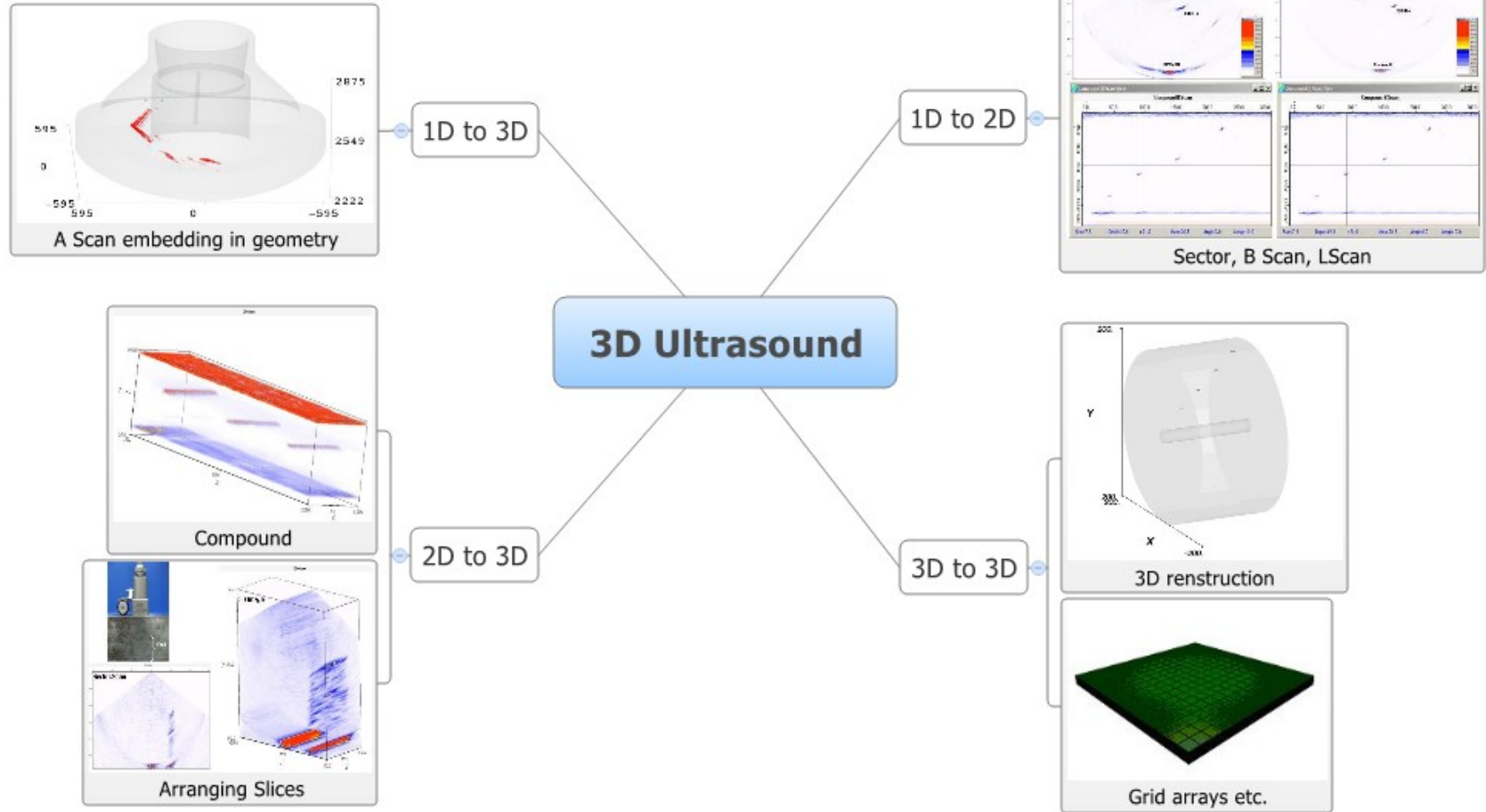
SEMINAR

R&D Laboratory on Industrial Demand

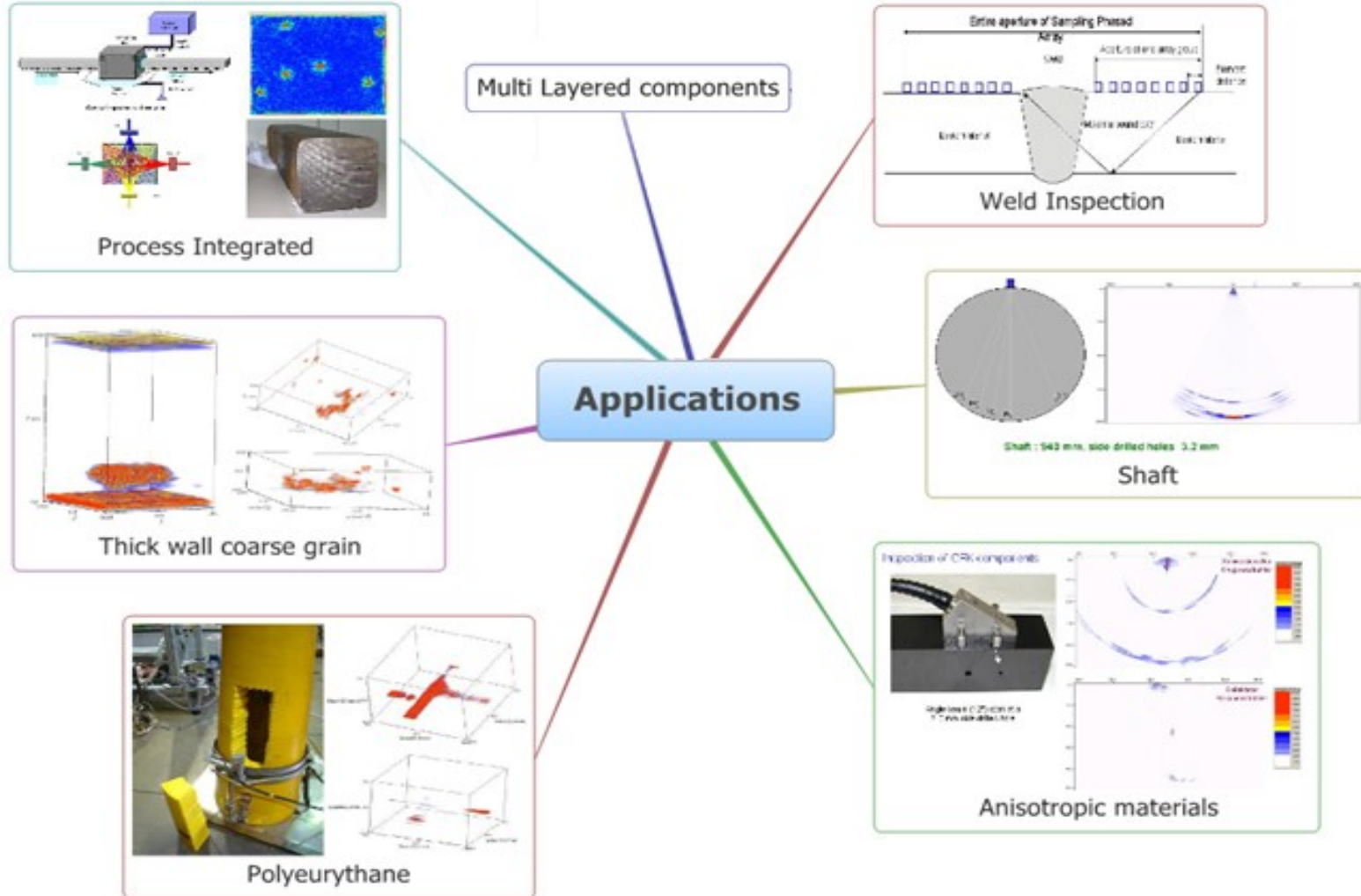


UT, μ -NDT, NDT Systems

Case Studies: Ultrasonic Imaging



Case Studies: Ultrasonic Imaging



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COFFEE BREAK

UT, μ -NDT, NDT Systems

Day 2:	Organization and Networks	Speaker
9.00	Welcome Address with Minutes of Last Day	NN
9.30	Recommended Laboratory Structure of Activities	Kröning
10.00	Human Resources – Ethics, Responsibilities, Education, Training and Certification	Klimenov
10.30	Coffee Break	
11.00	Methods I - ET, MT, PT, TT, VT	Vavilov
11.30	X-ray, Betatron	Klimenov
12.00	UT, μ -NDT, NDT Systems	Kröning
12.30	Open Round Discussion (Questions)	all
13.00	Lunch Break	
14.00	Applied Technologies and Capability Networks	Kröning
14.30	Knowledge Strategies and Education	Klimenov
15.00	Coffee Break	
15.30	Added Value Chain in Applied Science	Vavilov
16.00	R&D Driven by Demand – a Project Analysis	Kröning
16.30	Concluding Minutes	to be appointed
17.00	End of Second Day	

<u>Day 3:</u>	CASE STUDIES & NEXT STEPS	Speaker
9.00	Welcome Address with Minutes of Last Day	NN
9.30	Case Studies: Betatron for NDT	Klimenov
10.00	Advanced UT and New Instruments	Kröning
10.30	Coffee Break	
11.00	Thermography for Surface Characterization	Vavilov
11.30	NDT System for In-line NDT	Kröning
12.00	International Cooperation Practice	Klimenov
12.30	Open Round Discussion (Questions)	all NN
13.00	Lunch Break	
14.00	Next Steps and Seminar Evaluation	
16.00	End of Third Day	